# **Durable dual-state duplex Si–HfO<sup>2</sup> with excellent oxidation and cracking resistance**

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Abstract: The lifetime of Si bond coatings in environmental barrier coatings is constrained by phase-transition-induced cracking of the  $SiO<sub>2</sub>$  scale. In this study, Si–HfO<sub>2</sub> dual-state duplex composite materials are proposed to address this issue by partially forming HfSiO<sub>4</sub> and minimizing the SiO<sub>2</sub> content. The as-prepared composite exhibited a structure comprising discrete HfO<sub>2</sub> "bricks" embedded in a continuous Si "mortar", while the oxidized state transformed into discrete HfSiO<sub>4</sub> "bricks" within continuous thin SiO<sub>2</sub> "mortars". The results indicate that continuous thin SiO<sub>2</sub> contributes to reducing the oxidation rate to a level comparable to that of pure Si, and discrete  $HfSiO<sub>4</sub>$  particles aid in relieving phase transition-induced stress and inhibiting crack propagation, thereby enhancing oxidation and cracking resistance simultaneously. Consequently, the composite with 20 mol% HfO<sub>2</sub> and a mean particle size of ~500 nm at 1370 ℃ exhibited a service lifetime 10 times greater than that of pure Si. This research provides valuable insights for designing Si-based bond coatings with improved service lifetime.

**Keywords:** environmental barrier coatings (EBCs); bond coatings; oxidation; phase transition; cracking

# **1 Introduction**

Ceramic matrix composites (CMCs), especially  $SiC_f/SiC_m$ , are being used in new generations of propulsion materials in highpressure turbines due to their excellent high-temperature mechanical properties [\[1](#page-13-0)[,2](#page-13-1)]. However, they suffer from rapid recession by water vapor and oxidizers in gas turbine environments [\[3](#page-13-2)[,4](#page-13-3)]. Environmental barrier coatings (EBCs) are used as key protection agents for inhibiting the rapid recession of SiC<sub>t</sub>/SiC<sub>m</sub>composites [[5](#page-13-4)–7]. EBCs typically consist of a Si bond coating and a rare-earth silicate top coating [\[8](#page-13-6)]. During service at  $\geq$  1300 °C, a SiO<sub>2</sub> thermally grown oxide (TGO) layer is produced between the Si bond coating and the top coating, which is primarily composed of β-cristobalite [\[9](#page-13-7)[,10](#page-13-8)]. However, the transformation from β-cristobalite to α-cristobalite occurs at ~220 ℃ and is accompanied by a 4.5% volume contraction  $[8,11]$  $[8,11]$  $[8,11]$ . As a result, large elastic strain energy is generated, causing severe TGO microcracking and premature spalling of the EBCs [\[12](#page-13-10),[13](#page-13-11)]. Therefore, suppressing the  $SiO<sub>2</sub>$  phase transition is extremely important for realizing long-lifetime operation of EBCs.

To eliminate this unexpected phase transition, Si-stabilizer  $(Al_2O_3$  or mullite) duplex coatings and Si-HfO<sub>2</sub> composite coatings have been proposed [[14](#page-13-12)]. In Si-stabilizer duplex coatings, the diffusion of Al from the stabilizer to the  $SiO<sub>2</sub>$  scale causes hightemperature  $β$ -SiO<sub>2</sub> to retain metastability at room temperature, thus preventing phase-transition-induced cracking. However, the  $SiO<sub>2</sub>$  growth rates in Si-stabilizer duplex coatings are twice as high

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as those in pure Si coatings at 1350 °C due to the entry of  $Al^{3+}$  into the crystalline  $SiO<sub>2</sub>$  lattice, leading to the formation of additional oxygen vacancies. In Si-HfO<sub>2</sub> composite coatings, suppression of the phase transition relies on the reaction between  $SiO<sub>2</sub>$  and  $HfO<sub>2</sub>$ to form  $HfSiO_4$  [\[13](#page-13-11)[,15](#page-13-13),[16](#page-13-14)]. Nevertheless, the continuous  $HfO_2$ phase in the composite serves as an oxygen conduit, and the discontinuous Si phase has a high surface area. Once Si is oxidized, the composite coating will not provide any effective protection to the SiC substrate, resulting in premature cracking along the coating/substrate interface [\[17](#page-13-15)[,18](#page-13-16)]. These findings underscore the limitations of  $Si-HfO<sub>2</sub>$  composite coatings in achieving long lifetime operation of EBCs.

The li[m](#page-13-14)itations of  $Si-HfO<sub>2</sub>$  composite coati[ngs](#page-13-11) [ste](#page-13-13)m from the inappropriate distribution of the  $HfO<sub>2</sub>$  phase [\[13](#page-13-11),[15](#page-13-13)[,16](#page-13-14)]. On the one hand, oxidation of the SiC substrate can be avoided if the HfO<sub>2</sub> phase exhibits a discrete distribution. On the other hand, the HfO<sub>2</sub> particle size inside the composite coating should be redesigned to achieve a synergistic effect between the oxidation (formation of  $SiO<sub>2</sub>$ ) and reaction (formation of  $HfSiO<sub>4</sub>$ ) kinetics, thereby minimizing the amount of  $SiO_2$ . Therefore,  $Si-HfO_2$ composite coatings can simultaneously inhibit phase transitions and reduce oxidation rates. To increase the service lifetime, careful consideration of the  $HfO<sub>2</sub>$  content and distribution is paramount. However,  $Si-HfO<sub>2</sub>$  composite coatings reportedly exhibit high  $HfO<sub>2</sub>$  $HfO<sub>2</sub>$  $HfO<sub>2</sub>$  [co](#page-13-14)ntent (> 36 mol%) and a continuous distribution [\[13](#page-13-11)[,15](#page-13-13)[,16](#page-13-14)].

This study introduces a novel Si-HfO<sub>2</sub> dual-state duplex composite structure with discrete HfO<sub>2</sub> "bricks" and continuous Si "mortars" in the as-prepared state. After oxidation, it transforms into a structure with discrete  $HfSiO<sub>4</sub>$  "bricks" and

continuous thin  $SiO_2$  "mortars". Continuous thin  $SiO_2$  reduces the oxidation rate, and discrete  $HfSiO<sub>4</sub>$  particles alleviate phasetransition-induced stress, thereby enhancing the oxidation and cracking resistance simultaneously. Compared to that of pure Si, the composite shows a 10-fold longer service lifetime at 1370 ℃, with a comparable oxidation rate. This research offers insights into designing Si-based composite bond coatings with enhanced service lifetime for EBCs.

# **2 Design of the Si–HfO<sup>2</sup> dual-state duplex composite structure**

<span id="page-1-0"></span>The phase transition of  $SiO<sub>2</sub>$  causes a 4.5% volume contraction, [w](#page-13-6)[hich](#page-13-9) produces a large elastic strain energy inside the  $SiO<sub>2</sub>$  s[cal](#page-13-8)e [[8,](#page-13-6)[11](#page-13-9)].However,  $SiO<sub>2</sub>$  has a low fracture toughness [[10](#page-13-8)]. Consequently, severe cracking or spallation occurred [\(Fig. 1](#page-1-0)(a)). For channel cracking, the critical TGO thickness (*h<sub>c</sub>*) dictates

$$
h_{\rm c} = \frac{\gamma}{g_0 \varepsilon_0^2 \bar{E}} \tag{1}
$$

 $\bar{E} = E_0 / (1 - v_0^2)$  is the plane strain modulus, where  $E_0$  and  $v_0$ where  $\varepsilon_0$ ,  $g_0$ , and  $\gamma$  are the phase-transition-induced strain (~1%) [\[10](#page-13-8)], dimensionless parameter, and fracture energy, respectively. are the modulus and Poisson's ratio of  $SiO<sub>2</sub>$  TGO, respectively. Below the critical thickness, channel cracking is suppressed. For the pure Si coating, the  $h_c$  value is estimated to be 1.3  $\mu$ m, which is consistent with the reported experimental value of  $\sim$ 1.5  $\mu$ m [\[8](#page-13-6),[13](#page-13-11)].

During the oxidation of the  $Si-HfO<sub>2</sub>$  composite, both  $SiO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$  formed, and the  $SiO<sub>2</sub>$  scale was divided by  $HfSiO<sub>4</sub>$  particles [\(Fig.](#page-1-0) 1(b)). HfSiO<sub>4</sub> has a greater fracture toughness than  $SiO<sub>2</sub>$ 



Fig. 1 Schematic diagram of cracking behavior of (a) pure Si and (b) Si–HfO<sub>2</sub> composite after oxidation. (c) Two-dimensional simplified structure of the Si–HfO<sub>2</sub> composite and (d) stress distribution after the SiO<sub>2</sub> phase transition, (e) dependence of stress and (f) critical thickness on the HfO<sub>2</sub> content in the Si–HfO<sub>2</sub> composites.



[[19](#page-13-17)[,20](#page-13-18)]. As a result, when a crack encounters an  $HfSiO<sub>4</sub>$  particle, propagation occurs along the  $HfSiO<sub>4</sub>-SiO<sub>2</sub>$  interface. Compared with those in the pure Si sample, the cracks in the  $Si-HfO<sub>2</sub>$ composite exhibited more zigzag shapes, indicating greater cracking resistance. Moreover, when Si oxidizes to  $SiO<sub>2</sub>$  and then transforms to  $H\text{SiO}_4$ , the volume increase is calculated to be 14.8%  $[13,21]$  $[13,21]$  $[13,21]$ . Thus, HfSiO<sub>4</sub> grows under compressive stress. The residual compressive stress helps to alleviate the tensile stresses caused by the  $SiO<sub>2</sub>$  phase transition. As expected,  $HfSiO<sub>4</sub>$  particles result in stress redistribution in  $SiO<sub>2</sub>$  and the formation of a stress relief zone. To demonstrate the stress release, a 2D simplified model consisting of  $SiO<sub>2</sub>$  and  $HSiO<sub>4</sub>$  was constructed [\(Fig. 1](#page-1-0)(c)), and finite element analysis (FEA) was conducted. The FEA results confirmed the existence of a stress relief zone [\(Fig. 1](#page-1-0)(d)). The stress relief relies on the HfO<sub>2</sub> content and follows an exponential relationship [\(Fig.](#page-1-0) 1(e)). Moreover, stress relief contributes to increasing the critical TGO thickness  $(h<sub>c</sub>$  [Fig. 1](#page-1-0)(f)). Compared to that of pure Si, the stress in the Si-HfO<sub>2</sub> composite with 20 mol% HfO<sub>2</sub>was reduced by 25% ([Fig. 1](#page-1-0)(e)). [This](#page-1-0) resulted in a 78% increase in the critical TGO thickness [\(Fig. 1](#page-1-0)(f)). These results indicate that the addition of  $HfO<sub>2</sub>$  to the Si-HfO<sub>2</sub> composite contributes to both reducing the cracking stress and increasing the cracking resistance.

To completely eliminate the  $SiO<sub>2</sub>$  phase transition, a  $Si-HfO<sub>2</sub>$ compositewith 50 mol%  $HfO<sub>2</sub>$  is o[ptim](#page-13-15)al. However, both  $HfO<sub>2</sub>$ and  $HfSiO<sub>4</sub>$  are oxygen conduits [\[17](#page-13-15)]. A high  $HfO<sub>2</sub>$  content inevitably results in the continuous distribution of  $HfO<sub>2</sub>$  and HfSiO<sup>4</sup> , thus reducing its oxidation resistance. In addition, the coefficient of therma[l](#page-13-13) [exp](#page-13-15)[an](#page-13-20)sion (CTE) of  $HfO<sub>2</sub>$  is 6.46×[10](#page-13-8)<sup>-6</sup>–7.72×10<sup>-6</sup> K<sup>-1</sup> [15–[17,](#page-13-15)[22\]](#page-13-20), which is higher than that of  $SiC_f/SiC$  CMCs [\[10](#page-13-8)]. Therefore, a higher  $HfO_2$  content produces a greater thermal mismatch stress during [the](#page-13-13)[rm](#page-13-16)al cycling, causing premature cracking and delamination [\[15](#page-13-13)[,18](#page-13-16)]. Therefore, it is important to control the  $HfO<sub>2</sub>$  content to balance the need for antioxidation and anti-cracking.

In response to these challenges, this study proposes a new  $Si-HfO<sub>2</sub>$  dual-state duplex composite structure. The as-prepared composite consists of discrete HfO<sub>2</sub> "bricks" and continuous Si "mortars", transforming into a structure with discrete  $HfSiO<sub>4</sub>$ "bricks" and continuous thin  $SiO<sub>2</sub>$  "mortars" after oxidation. This design aims to simultaneously reduce the oxidation rate and relieve phase-transition-induced stress.

### **3 Experimental**

#### **3.1 Composite preparation and isothermal oxidation**

It is crucial to hi[ghl](#page-13-15)i[gh](#page-13-19)t that both  $HfO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$  function as oxygen conduits [\[17](#page-13-15),[21](#page-13-19)]. Consequently, a discrete distribution of  $HfO<sub>2</sub>$  particles in the Si–HfO<sub>2</sub> composite is imperative. To obtain a discrete distribution of  $HfO<sub>2</sub>$  particles, the sizes of the Si powders must be smaller than those of the  $HfO<sub>2</sub>$  powders. Ho[wev](#page-13-13)[er,](#page-13-14) [thi](#page-13-21)s consideration was often overlooked in prior studies [\[15](#page-13-13)[,16](#page-13-14),[23](#page-13-21)], leading to rapid oxidation of Si and SiC substrates. According to fracture mechanics, smaller particle sizes [wi](#page-13-22)th the same  $HfO<sub>2</sub>$ content indicate greater cracking resistance [\[24](#page-13-22)]. However, smaller particles [exh](#page-13-11)[ibit](#page-13-17) lower thermal stability, leading to Ostwald ripening  $[13,19]$  $[13,19]$  $[13,19]$ . HfO<sub>2</sub> particles of ~280 n[m](#page-13-11) in size have demonstrated stability for 1000 h at 1250 °C [[13](#page-13-11)]. To ensure thermal stability at 1370 ℃, HfO<sub>2</sub> particles ranging in size from 300 to 800 nm were selected.

In an effort to suppress the  $SiO<sub>2</sub>$  phase transition, a high concentration of  $HfO<sub>2</sub>$  (> 36 mol%) was incorporated into Si-HfO<sub>2</sub> composite coatings [\[13](#page-13-11),[16](#page-13-14)[,23](#page-13-21),[25\]](#page-13-23). However, a high  $HfO<sub>2</sub>$ content results in a continuous distribution of  $HfO<sub>2</sub>$  particles. Although lower HfO<sub>2</sub> contents  $(< 25$  mol%) have been explored, reported Si-HfO<sub>2</sub> composite coatings still exhibit a continuous distribution of HfO<sub>2</sub> particles due to the larger Si particle size compared to that of  $HfO<sub>2</sub>$  [\[15](#page-13-13)[,17](#page-13-15)]. In this study, Si-HfO<sub>2</sub> samples were prepared with  $HfO<sub>2</sub>$  contents of 10 mol%, 20 mol%, and 30 mol%, denoted as Si10Hf, Si20Hf, and Si30Hf, respectively. The Si powders (99.99%, Shanghai STNANO Science & Technology Co., Ltd.) ranged from 100 to 200 nm in size. Dual-scale  $\rm{HfO_2}$  raw powders were utilized for Si-HfO<sub>2</sub> composite preparation, in which finer  $HfO<sub>2</sub>$  powders (500-1500 nm, 99.99%, Quannan Jingxin Environmental Protection Materials Co., Ltd.) were incorporated to eliminate  $SiO<sub>2</sub>$  and coarser particles (2–10 µm) to enhance the creep strength at 1370 °C [[17,](#page-13-15)[18\]](#page-13-16). According to stoichiometric ratios, Si and  $HfO<sub>2</sub>$  powders were mixed through ball milling in a  $Si<sub>3</sub>N<sub>4</sub>$  jar with ZrO<sub>2</sub> balls for 12 h at a rotation speed of 5 r·s<sup>-1</sup>. The diameter of the milling jar was 50 mm. The ball-to-powder mass ratio was 8 : 1. Hydraulic pressing (at 300 MPa pressure) was used to form green bodies with a diameter of 10 mm and a thickness of 1 mm. The subsequent dense  $Si-HfO<sub>2</sub>$  composites were prepared through two-step sintering in an argon atmosphere, initially at 1100 ℃ for 20 h, followed by 1370 ℃ for 8 h, with a heating and cooling rate of 4 ℃·min–1 .

For the isotherm[al](#page-13-8) [oxid](#page-13-12)ation test, the detailed procedures can be found in Refs.[[10](#page-13-8)[,14](#page-13-12)]. The melting point of Si is 1414 ℃, which can be substantially lower in the presence of impurities. This limi[ts t](#page-13-15)he use temperature of Si coatings to typically less than 1316 ℃ [\[17](#page-13-15)]. In [ad](#page-13-12)dition, the oxidation of Si coatings is sensitive to temperature [\[14](#page-13-12)]. Therefore, to accelerate the evaluation of the oxidation kinetics and failure behaviors of the composites, the oxidation temperature in this study was set to 1370 ℃. Oxidation at 1300 ℃ was also conducted for comparison. Isothermal durations included 5, 10, 50, 100, 150, and 200 h, with a heating and cooling rate of 4 ℃·min–1 during oxidation.

#### **3.2 Microstructural characterization**

The surface and cross-sectional microstructures of the composites were examined using scanning electron microscopy (SEM, VEGA II-XMU, TESCAN). The elemental distributions were analyzed via energy dispersive spectroscopy (EDS, AZTEC, Oxford Instruments) integrated into the SEM. The acceleration voltage and working distance used for EDS testing were 15 kV and 15 mm, respectively. The X-ray diffraction (XRD, D8advance 3.0, Bruker) was utilized to identify the phase composition within a 2*θ* range of 10°–90°. The samples were scanned with a step size of 0.1° and a velocity of 2 (°)·min–1 . Semi-quantitative analysis of the relative [pha](#page-13-10)[se](#page-13-24) [com](#page-13-25)position was conducted by comparing peak intensities [\[12](#page-13-10)[,26](#page-13-24)[,27](#page-13-25)]. Additionally, TGO thickness was measured via Demo VegaTC software, which was integrated into the SEM.

The atomic structures were investigated through scanning transmission electron microscope (FSTEM, JEM-F200, operating at 200 kV). TEM samples were prepared using a focused ion beam (FIB, FEI Quanta 200 FEG). Amorphous layers generated during FIB preparation were removed using a Nano Mill (M1040 Nano Mill, Fischione) with argon ions (Ar<sup>+</sup>) as the cleaning agent at an ion energy of 700 eV and a milling angle of 30°. The faces of the samples were milled for 30 min. The fracture toughness of the sintered composites was measured through Vickers hardness indentation at a load of 1 kgf with a dwell time of 10 s. A nanoindentation test was conducted with an Agilent Nano Indenter G200 instrument at a load of 150 mN and a dwell time

of 10 s to obtain the modulus.

The surface/interface energies and density of states of  $HfSiO<sub>4</sub> - SiO<sub>2</sub>$  and  $HfO<sub>2</sub> - SiO<sub>2</sub>$  were investigated through firstprinciples calculations. Structures and surfaces were constructed using Materials Studio software, and calculations were performed in the Vienna *ab initio* simulation package (VASP). Electronic exchange-correlation interactions were handled with projector augmented wave (PAW) and generalized-gradient approximation (GGA) using the Perdew, Burke, and Ernzerhof (PBE) pseudopotential. The cutoff energy of the plane wavefunction was set to 350 eV, and *K*-points were set to 4×4×6. Geometry optimizations were performed using conjugate gradient minimization until all the forces acting on the ions were less than 10–8 eV·Å–1 per atom. *Ab initio* molecular dynamics simulations of the optimized structures were performed using DFT semi-pseudopotential processing kernels, NVT ensembles, atmospheric pressure, a temperature of 1400 ℃, and a time step of 1 fs for a total simulation time of 10 ps.

## **4 Results**

# **4.1 Phase composition and microstructure of the asprepared Si–HfO<sup>2</sup> composites**

<span id="page-3-0"></span>Due to the two-step sintering process with an argon atmosphere, dense Si-HfO<sub>2</sub> composites were prepared [\(Figs. 2](#page-3-0)(a) and 2(b)). The Feret diameter distribution of the  $HfO<sub>2</sub>$  particles was measured using ImageJ software at a magnification of 5000 times.

The statistical area was  $> 26,000 \mu m^2$ . The HfO<sub>2</sub> particle size ranges from approximately 300 to 800 nm, with an average value of ~500 nm in the composite. During composite preparation, only Si (cubic) and  $HfO<sub>2</sub>$  (monoclinic, m-HfO<sub>2</sub>) phases were detected [\(Fig.](#page-3-0) 2(c)). This indicates that  $HfO<sub>2</sub>$  and Si can form a stable composite structure at 1370 ℃. The main peaks of the Si and m-HfO<sub>2</sub> phases are at (111), with corresponding 2θ values of 28.4° and  $31.7^\circ$ , respectively. The HfO<sub>2</sub> phase contents in the asprepared Si10Hf, Si20Hf, and Si30Hf composites were estimated to be 13, 20, and 29 mol%, respectively, which were consistent with the set values. Compared with that of pure Si, the fracture toughness of the Si10Hf, Si20Hf, and [Si30H](#page-3-0)f composites increased by 20%, 44%, and 131%, respectively [\(Fig. 2](#page-3-0)(d)). This is consistent with the reported values ranging between 1.38 and 1.52 MPa·m<sup>1/2</sup> for the Si-rich ph[ase](#page-13-18) a[nd betwe](#page-3-0)en 2.26 and 2.38 MPa·m<sup>1/2</sup> for the HfO<sub>2</sub>-rich phase [\[20](#page-13-18)]. [Figure](#page-3-0) 2(e) shows the load-displacement curves of the as-prepared composites. According to the hysteresis, the moduli for Si, Si10Hf, Si20Hf, and Si30Hf are estimated to be 183, 144, 139, and 154 GPa, respectively. This is consistent with the reported values of 205 and 157 GPa for pure [Si](#page-13-26) and Si-HfO<sub>2</sub> composites,respectively (with 36 mol% HfO<sub>2</sub>) [[28](#page-13-26)]. Compared with that of pure Si, the modulus [of](#page-13-27) Si20Hf decreases by 25%, indicating a higher strain tolerance [\[29](#page-13-27)]. These results underscore the stability achieved at 1370 °C for Si–HfO<sub>2</sub> composites with a mean particle size of ~500 nm and the beneficial influence of  $HfO<sub>2</sub>$  on the fracture toughness of Si-HfO<sub>2</sub> composites.



Fig. 2 (a) Surface and (b) cross-sectional microstructures, (c) XRD patterns, (d) toughness, and (e) load-displacement of the as-prepared Si–HfO<sub>2</sub> composites.



#### **4.2 Structural evolutions during isothermal oxidation**

[Figure 3](#page-4-0) shows the XRD patterns of the thermally grown oxides at room temperature. The tetragonal  $HfSiO<sub>4</sub>$  phase was detected after 5 h of oxidation at 1370 °C ([Figs. 3](#page-4-0)(a)–3(c)), confirming the rapid reaction between  $SiO_2$  and  $HfO_2$  [\[30](#page-13-28)]. Moreover, the α-SiO<sub>2</sub> phase was detected, indicating the occurrence of the β  $\rightarrow \alpha$  phase transition  $[10,13]$  $[10,13]$  $[10,13]$ . It has been reported that  $Al^{3+}$  can enter the lattice of crystalline SiO<sub>2</sub>, thus suppressing the β  $\rightarrow \alpha$  phase transition[[14](#page-13-12)[,27](#page-13-25)[,31](#page-13-29)]. However, only the  $\alpha$ -SiO<sub>2</sub> phase was detected in this study, indicating that  $HfO<sub>2</sub>$  addition cannot suppress the  $\beta \rightarrow \alpha$  phase transition by a lattice solid. This may be because the ionic radius of  $Hf<sup>4+</sup>$  (0.83 Å) is much larger than the ionic radius of  $Si^{4+}$  (0.54 Å) [\[32](#page-13-30)]. As a result, HfO<sub>2</sub> is insoluble in

crystalline  $SiO_2$ . The main peaks of the tetragonal  $\alpha$ -SiO<sub>2</sub> and HfSiO<sup>4</sup> phases are at (200), with corresponding 2*θ* values of 36.0° and 27.1°, respectively. In addition, compared with those of the  $\alpha$ -SiO<sub>2</sub> phase, higher peak intensities of the HfSiO<sub>4</sub> phase were observed (Figs.  $3(a)-3(c)$ ). This indicates the synergistic effects of oxidation (formation of  $SiO<sub>2</sub>$ ) and reaction (formation of  $HfSiO<sub>4</sub>$ ) kinetics. This is consistent with the report that the net thickness of  $SiO<sub>2</sub>$  on a Si-HfO<sub>2</sub> duplex de[crea](#page-13-28)sed by at least a factor of two compared to that on [pure](#page-3-0) Si [\[30](#page-13-28)]. In contrast to that of the asprepared composites (Fig.  $2((c))$ , the main peak of the m-HfO<sub>2</sub> phase is at (300), with a corresponding 2*θ* value of 54.4°. In addition, compared with that of the  $HfO<sub>2</sub>$  phase, the  $HfSiO<sub>4</sub>$  phase content significantly increased [\(Fig.](#page-4-0) 3(d)). This suggests the

<span id="page-4-0"></span>

**Fig. 3** XRD patterns of the thermally grown oxides at room temperature: (a) Si10Hf, (b) Si20Hf, and (c) Si30Hf oxidized at 1370 ℃. (d) HfSiO<sub>4</sub> phase content versus oxidation time.

enrichment of  $HfSiO<sub>4</sub>$  particles on the surface and the occurrence of phase separation between  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$ . These results indicate that the  $SiO<sub>2</sub>$  phase transition was partially eliminated by the formation of HfSiO<sub>4</sub>. Therefore, determining the distribution of HfO<sub>2</sub> particles in composites is crucial for minimizing the  $SiO<sub>2</sub>$ content.

[Figure](#page-5-0) 4 shows the surface morphologies of the  $Si-HfO<sub>2</sub>$ composites after oxidation at 1370 ℃. With increasing oxidation time, the HfSiO<sub>4</sub> particles agglomerate [\(Figs. 4](#page-5-0)(b), 4(d), and 4(f)), which is consistent with the XRD observations [\(Fig.](#page-4-0)  $3(d)$ ). Notably, networked cracks appeared on the surface of the Si10Hf composite after 100 h of oxidation [\(Fig.](#page-5-0) 4(b)). However, few discrete cracks were observed on the surface of the Si20Hf and Si30Hf composites after 100 h of oxidation [\(Figs. 4](#page-5-0)(d) and 4(f)). In comparison, networked cracks were observed on the surface of the pure Si coatings after 10 h of oxidation at 1300 ℃ [\[10](#page-13-8)[,14](#page-13-12)]. In this study, the lifetime was defined on the basis of the integrity of TGO [\[14](#page-13-12)], namely, its ability to protect the underlying composite from oxidation. These results indicate that, compared with the service lifetime of pure Si, the lifetime of the Si20Hf and Si30Hf composites at 1370 ℃ increase by more than 10 times. Furthermore, compared with those of the Si20Hf composite, the  $HfO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$  phases exhibit a continuous distribution in the Si30Hf composite [\(Fig. 4](#page-5-0)(f)). The continuous  $HfO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$ phases act as oxygen conduits, probably resulting in accelerated oxidation [\[17](#page-13-15)]. These results indicate that the  $Si-HfO<sub>2</sub>$  composites with 20 mol%  $HfO<sub>2</sub>$  have optimal resistance to cracking and oxidation.

[Figure](#page-6-0) 5 shows the cross-sectional microstructures of the Si–HfO<sub>2</sub> composites after oxidation. The HfO<sub>2</sub> particles maintained a mean size of  $~500$  nm inside the composites, comparableto that of the as-prepared composites  $(Fig. 2(a))$  $(Fig. 2(a))$  $(Fig. 2(a))$ , signifying high thermal stability at 1370 ℃. This is consistent with the finding that  $HfO<sub>2</sub>$  particles  $\sim$ 350 nm in size remained stable for 1000 h at 1250 °C [\[13](#page-13-11)]. However, compared with that of the  $HfO<sub>2</sub>$  particles, the size of the  $HfSiO<sub>4</sub>$  particles significantly increased. Additionally, in agreement with the XRD results [\(Fig. 3](#page-4-0)(d)), HfSiO<sub>4</sub> particles were enriched on the surface of the  $SiO<sub>2</sub>$  scale, confirming the occurrence of phase separation between  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$ . A similar phenomenon was noted for  $Si-HfO<sub>2</sub>$ 

<span id="page-5-0"></span>

**Fig. 4** Surface morphologies of (a, b) Si10Hf, (c, d) Si20Hf, and (e, f) Si30Hf composites after 10 and 100 h of isothermal oxidation at 1370 ℃, respectively.



coatings during oxidation at 1250 ℃ [\[13](#page-13-11)]. The observed phase separation is not conducive to inhibiting phase-transition-induced cracking. Notably, no delamination occurred at the interface between the  $\rm SiO_2$  scale and the  $\rm Si-HfO_2$  composite after 100 h of oxidation at 1370 ℃. In contrast, interfacial delamination was evident in pure Si after 20 h of oxidation at 1300 ℃, where it reached a spallation area ratio of 50% after 48 h of oxidation at 1350 °C [[10](#page-13-8)[,14](#page-13-12)]. These results indicate that  $HfO<sub>2</sub>$  particles with a mean value of ~500 nm have high thermal stability at 1370 ℃ and that HfO<sub>2</sub> addition greatly extends the cracking resistance of pure Si.

# **4.3 Si oxidation kinetics**

The growth of  $SiO<sub>2</sub>$  TGOs on pure Si coatings follows a parabolic law [\[10](#page-13-8),[14](#page-13-12)]. Parabolic kinetics imply that the growth rate relies on oxygen transport in  $SiO<sub>2</sub> TGOs$  through grain boundary diffusion [ $14,33$  $14,33$ ]. Despite HfO<sub>2</sub> serving as an oxygen conduit, the oxidation of Si–HfO<sub>2</sub> composites also follows parabolic kinetics [\(Fig. 6](#page-7-0)). The fitted growth rates are presented in [Table](#page-7-1) 1. For pure Si, the oxidation rates are 0.46 and 0.61  $\mu$ m·h<sup>-1/2</sup> at 1300 and 1370 ℃, respectively, which are consistent with the reported values of 0.5 μm·h<sup>-1/2</sup> at 1300 °C [[10,](#page-13-8)[14](#page-13-12)]. However, smaller and larger values of 0.16 and 1.2  $\mu$ m·h<sup>-1/2</sup> are reported for pure Si coatings at 1250 and 1350 ℃, respectively [\[13](#page-13-11)[,14](#page-13-12)], suggesting that temperature significantly influences the oxidation rate of the pure Si coating. Due to the discrete distribution of  $HfO<sub>2</sub>$  particles and the continuous thin SiO<sub>2</sub> "mortars" [\(Figs. 4](#page-5-0)(b) and 4(d)), the Si10Hf and Si20Hf composites exhibit oxidation rates comparable to those of pure Si at both 1300 and 1370 ℃ [\(Table 1](#page-7-1)). This is attributed to the HfO<sub>2</sub> powder being larger than the Si powder during composite preparation. In contrast, a composite structure with  $\sim$ 100 nm HfO<sub>2</sub> and  $\sim$ 10 µm Si exhibited a continuous distribution of  $HfO<sub>2</sub>$ , resulting in SiC substrate oxidation [\[15](#page-13-13)]. These results indicate that, in contrast to reported  $Si-HfO<sub>2</sub>$  powders with larger Si particle sizes than  $HfO<sub>2</sub>$  [\[15](#page-13-13),[16](#page-13-14)[,18](#page-13-16)[,25](#page-13-23)], the smaller Si particle size contributes to the discrete distribution of  $\rm{HfO}_{2}$ .

Due to the continuous distribution of  $HfO<sub>2</sub>$  particles and discrete  $SiO<sub>2</sub>$  "mortars" ([Figs. 4](#page-5-0)(f) and 5(f)), the oxidation rates of the Si30Hf composites are 1.6 and 1.8 times greater than those of pure Si at 1300 and 1370 ℃, respectively [\(Table 1](#page-7-1)). This finding aligns with a previous report indicating complete oxidation of free

<span id="page-6-0"></span>

**Fig. 5** Cross-sectional microstructures of (a, b) Si10Hf, (c, d) Si20Hf, and (e, f) Si30Hf composites after 10 and 100 h of isothermal oxidation at 1370 ℃, respectively.

Si inside a 50  $\mu$ m thick Si-HfO<sub>2</sub> coating (25/75 mol% HfO<sub>2</sub>/Si) within 10 h at 1370 °C [\[17](#page-13-15)]. The oxidation rate is 16.3 times that of the Si30Hf composite. Additionally, the fitted oxidation rates are approximately 2.2 and 2.1  $\mu$ m·h<sup>-1/2</sup> for the Si-Al<sub>2</sub>O<sub>3</sub> and Si–mullite duplex coatings, respectively, at 1350 ℃ [[10,](#page-13-8)[14](#page-13-12)]; these values are much greater than the current values. This is attributed to  $Al^{3+}$  entering the lattice of crystalline  $SiO_2$ , creating additional oxygen vacancies. These results indicate that a discrete distribution of  $HfO<sub>2</sub>$  particles in Si– $HfO<sub>2</sub>$  composites can form a continuous thin  $SiO<sub>2</sub>$  "mortar", achieving a comparable oxidation rate to that of pure Si while suppressing phase-transition-induced cracking.

To minimize the  $SiO<sub>2</sub>$  phase transition, a high concentration of HfO<sub>2</sub> was added to the Si–HfO<sub>2</sub> composite coatings  $[13,16,23,25]$  $[13,16,23,25]$  $[13,16,23,25]$  $[13,16,23,25]$  $[13,16,23,25]$  $[13,16,23,25]$ . However, both continuous  $HfO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$  act as oxygen conduits [\[17](#page-13-15)[,21](#page-13-19)], resulting in a greater oxidation rate. The current study demonstrated that a discrete distribution of HfO<sub>2</sub> particles in Si–HfO<sub>2</sub> composites can yield a comparable oxidation rate to that of pure Si [\(Fig. 6](#page-7-0)).

## **4.4 HfSiO<sup>4</sup> formation kinetics**

In Si–HfO<sub>2</sub> composite coatings, the suppression of the  $SiO<sub>2</sub>$  phase transition is achieved through the reaction between  $SiO<sub>2</sub>$  and  $HfO<sub>2</sub>$  to form  $HfSiO<sub>4</sub>$  [\[13](#page-13-11),[16](#page-13-14)[,17](#page-13-15)]. Therefore, achieving synergy between oxidation (formation of  $SiO<sub>2</sub>$ ) and reaction (formation of HfSiO<sub>4</sub>) kinetics is crucial for minimizing the  $SiO<sub>2</sub>$  content. [Figures](#page-8-0) 7 and [8](#page-9-0) show the surface and cross-sectional microstructures of the HfSiO<sup>4</sup> particles after oxidation at 1370 ℃. Compared to those of the  $HfO<sub>2</sub>$  particles in the as-prepared composites ([Figs. 2](#page-3-0)(a) and 2(b)), the sizes of the  $HfSiO<sub>4</sub>$  particles significantly increased [\(Fig. 7](#page-8-0) and [Table 2](#page-9-1)). However, the size of the HfO<sub>2</sub> particles inside the composites remained relatively unchanged with increasing duration [\(Fig.](#page-6-0) 5), indicating high thermal stability at 1370 °C. The residual  $HfO<sub>2</sub>$  phases inside the HfSiO<sup>4</sup> particles exhibit a discrete island distribution. These findings suggest that a large  $HfSiO<sub>4</sub>$  island formed through the coalescence of smaller  $HfSiO<sub>4</sub>$  particles rather than through the coalescence of  $HfO<sub>2</sub>$  particles. The formation of  $HfSiO<sub>4</sub>$  occurs through the inward diffusion of  $SiO<sub>2</sub>$ , consistent with the findings of a previous report indicating that the diffusion of  $Hf<sup>4+</sup>$  is much slower than that of  $Si^{4+}$  and  $O^{2-}[34]$  $O^{2-}[34]$  $O^{2-}[34]$ . This difference is attributed to

the much larger ionic radius of  $Hf<sup>4+</sup>$  (0.83 Å) compared to that of  $Si<sup>4+</sup>$ (0.54 Å) [[32](#page-13-30)], coupled with the stronger interaction between  $Hf^{4+}$  and  $O^2$ . Furthermore, the  $HfSiO_4$  particles were enriched on the surface of the  $SiO<sub>2</sub>$  scale [\(Fig. 8](#page-9-0)), indicating phase separation between  $HfSiO_4$  and  $SiO_2$ . This is consistent with the XRD results [\(Fig. 3](#page-4-0)(d)). As the oxidation time increases from 10 to 100 h at 1370 °C, the average HfSiO<sub>4</sub> particle size increases from 1.10 to 1.28 μm in the Si20Hf composites [\(Table](#page-9-1) 2) and from 1.75 to 2.02 μm in the Si30Hf composites. A larger  $HfSiO<sub>4</sub>$  particle size is not conducive to improving the cracking resistance, as evidenced by cracks forming through the  $HfSiO<sub>4</sub>$  particles [\(Figs.](#page-8-0) 7(b) and 7(f)). Additionally, compared to that on the Si30Hf composite, the HfO<sub>2</sub> phase on the surface of the Si20Hf composite was almost completely consumed after 100 h of oxidation [\(Fig.](#page-8-0) 7(e)), effectively minimizing the  $SiO<sub>2</sub>$  content. These results indicate that the Si-HfO<sub>2</sub> composites with 20 mol% HfO<sub>2</sub> demonstrate optimal resistance to cracking and oxidation.

#### **4.5 Cracking behavior**

Due to phase-transition-induced cracking [\[10](#page-13-8)[,13](#page-13-11)[,14](#page-13-12)], networked cracks and interfacial delamination were observed on the surface of pure Si after 10 h of oxidation at 1300 °C [\(Fig. 9](#page-10-0)(a)). The  $SiO<sub>2</sub>$ thickness is ~1.7  $\mu$ m after 10 h of oxidation at 1300 °C [\(Fig. 6](#page-7-0)), which is consistent with the reported occurrence of channel cracking when the SiO<sub>2</sub> TGO thickness exceeds  $\sim$ 1.5  $\mu$ m [\[8](#page-13-6)[,13](#page-13-11)]. Similarly, networked cracks were observed on the Si10Hf composite [\(Fig. 9](#page-10-0)(b)), where the TGO thickness was  $\sim$ 2.0  $\mu$ m. This indicates that the addition of 10 mol%  $HfO<sub>2</sub>$  fails to suppress phase-transition-induced cracking. This is consistent with the prediction that the stress in the Si10Hf composite was reduced by only 9% compared to that in pure Si  $(Fig. 1(e))$  and that the critical TGO thickness  $(h<sub>c</sub>, Eq. (1))$  in the Si10Hf composite was only  $\sim$ 1.6 μm [\(Fig. 1](#page-1-0)(f)). This was confirmed by the observation of network cracks in the Si-HfO<sub>2</sub> coating with 11.7 mol%  $HfO<sub>2</sub>$  after 10 h of oxidation at 1300 ℃ [\[35](#page-13-33)]. However, few discrete cracks were observed on the surface of the Si20Hf and Si30Hf composites after 100 h of oxidation at 1370 ℃ [\(Figs. 9](#page-10-0)(d) and 9(e)), although the TGO thicknesses reached 5.4 and 9.4 μm, respectively. However, widespread delamination occurs in pure Si when the TGO thickness reaches 5.0 μm [\[9](#page-13-7)[,10](#page-13-8)[,14](#page-13-12)]. These results indicate that, compared with the service lifetime of pure Si, the lifetimes of

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**Table 1** Fitted growth rate for Si–HfO<sub>2</sub> composites during isothermal oxidation according to the data in Fig. 6 (Unit: μm·h<sup>-1/2</sup>)

<span id="page-7-1"></span><span id="page-7-0"></span>

**Fig. 6** Oxidation kinetics of the Si–HfO<sub>2</sub> composite at (a) 1300 ℃ and (b) 1370 ℃.

<span id="page-8-0"></span>

**Fig. 7** Surface morphologies of (a, c, e) Si20Hf and (b, d, f) Si30Hf composites after isothermal oxidation for 10, 50, and 100 h at 1370 ℃.

the Si20Hf and Si30Hf composites at 1370 ℃ increase by more than 10 times.

The crack widths in the Si10Hf and Si20Hf composites are smaller than those in pure Si [\(Figs.](#page-10-0)  $9(b)$  and  $9(d)$ ). The crack width (*w*) is proportional to the cracking strain [\[29](#page-13-27)], and it dictates

$$
w = g_1 \varepsilon_0 h \tag{2}
$$

where  $g_1$  is a dimensionless parameter and  $h$  is the TGO thickness. For no elastic mismatch,  $g_1 = 5.816$  [\[29](#page-13-27)]. Due to the discrete distribution of  $HfO<sub>2</sub>$  and  $HfSiO<sub>4</sub>$  particles [\(Figs. 4](#page-5-0)(b) and 4(d)), the Si10Hf and Si20Hf composites have TGO thicknesses comparable to that of pure Si [\(Fig. 6](#page-7-0) and [Table 1](#page-7-1)). This indicates that  $HfO<sub>2</sub>$ addition reduces the cracking stress induced by the  $SiO<sub>2</sub>$  phase transition. Furthermore, the crack path is along the edge of the HfSiO<sup>4</sup> particles [\(Figs. 9](#page-10-0)(b) and 9(d)), which is consistent with the fact that  $HfSiO_4$  has a larger fracture toughness than  $SiO_2$  [\[10](#page-13-8),[20](#page-13-18)]. However, although more  $H\text{SiO}_4$  is formed on the Si30Hf surface, the crack width is much larger than that in the pure Si and Si20Hf composites [\(Fig. 9](#page-10-0)(d)). This is because the TGO thickness of the Si30Hf composites is much greater than that of pure Si [\(Fig. 6](#page-7-0) and [Table](#page-7-1) 1). These results indicate that the cracking in  $Si-HfO<sub>2</sub>$ composites relies on both the content of  $HfSiO<sub>4</sub>$  particles and the thickness of the  $SiO<sub>2</sub>$  scale.

The crack spacing (*S*) is inversely proportional to the cracking strain [\[29](#page-13-27)] and dictates

$$
S = 2g_2 h \cdot \operatorname{arctanh}\left(\frac{\gamma}{g_2 h \overline{E} \varepsilon_0^2}\right) \tag{3}
$$

where  $g_2$  is a dimensionless parameter and the symbol arctanh represents the inverse hyperbolic tangent function. For no elastic mismatch, $g_2 = 1.976$  [[29](#page-13-27)]. The crack spacing of the Si10Hf composite is comparable to that of pure Si [\(Figs. 9](#page-10-0)(a) and 9(b)). However, the crack spacing in the Si20Hf composites is much greater than that in the pure Si and Si10Hf composites [\(Figs. 9](#page-10-0)(a), 9(b), and 9(d)). The Si20Hf composite has a TGO th[ickne](#page-7-0)ss comparable to that of the pure Si and Si10Hf composites ([Fig. 6](#page-7-0)). This indicates that the cracking strain  $(\varepsilon_0)$  in the Si20Hf composite



<span id="page-9-0"></span>

<span id="page-9-1"></span>**Fig. 8** Cross-sectional microstructures of (a, b) Si10Hf, (c, d) Si20Hf, and (e, f) Si30Hf composites after isothermal oxidation for 100 h at 1300 and 1370 ℃.

**Table 2** Average HfSiO<sub>4</sub> particle size during oxidation at 1370 ℃ (Unit: μm)

			Unit: um



is much lower than that in the pure Si and Si10Hf composites. This is consistent with the smaller cracking strain  $(\varepsilon_0)$  in the Si20Hf composite due to the higher  $HfSiO<sub>4</sub>$  content.

In brief, premature channel cracking occurred in the Si10Hf composite, indicating that the addition of 10 mol%  $HfO<sub>2</sub>$  failed to suppress phase transition-induced cracking. Although it has a larger crack spacing than that in the pure Si and Si10Hf composites, the Si30Hf composite has a larger crack width, indicating a smaller cracking strain and a larger TGO thickness. Among all the composites, Si20Hf has the smallest crack width and the largest spacing, indicating the optimal resistance to cracking and oxidation.

### **5 Discussion**

#### **5.1 Phase separation between HfSiO<sup>4</sup> and SiO<sup>2</sup>**

To elucidate the reason for phase separation, the surface and interface energies of  $H\text{SiO}_4-\text{SiO}_2$  and  $H\text{fO}_2-\text{SiO}_2$  were investigated through first-principles calculations. The results reveal that HfSiO<sub>4</sub> has a significantly lower surface en[ergy th](#page-11-0)an the interface energy between  $HfSiO_4$  and  $SiO_2$  [\(Fig.](#page-11-0) 10(a)). Additionally, the presence of vacancies at the interface between  $HfSiO<sub>4</sub>$  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$  also indicates susceptibility to phase separation [\(Fig. 1](#page-11-0)0(c)). Moreover, the low overlap of the density of state peaks between  $SiO<sub>2</sub>$  and HfSiO<sub>4</sub> (only three peaks) suggests



<span id="page-10-0"></span>

**Fig. 9** Distribution of mud cracks on the surface of (a) pure Si, (b) Si10Hf, (c) Si20Hf, and (d) Si30Hf composites after isothermal oxidation at 1370 ℃.

susceptibility to phase separation (Fig.  $10(d)$ ). The total band gaps at the  $H\text{SiO}_4-\text{SiO}_2$  and  $H\text{fO}_2-\text{SiO}_2$  interfaces are much narrower than those at the pure  $SiO_2$ , HfSiO<sub>4</sub>, and HfO<sub>2</sub> phases, and they exhibit a leftward shift [\(Fig. 1](#page-11-0)0(d)). This difference implies the possible presence of electron holes at the interface, indicating the instability of the  $HfSiO_4-SiO_2$  and  $HfO_2-SiO_2$  interfaces.  $HfO_2$ also has a lower surface energy than the interface energy between  $HfO<sub>2</sub>$  and SiO<sub>2</sub> [\(Fig. 1](#page-11-0)0(b)), signifying a substantial reaction driving force between  $HfO<sub>2</sub>$  and  $SiO<sub>2</sub>$ . This was confirmed by the formation of the tetragonal  $HfSiO<sub>4</sub>$  phase after only 5 h of isothermal oxidation [\(Fig. 3](#page-4-0)). These results indicate that the future direction for better antioxidative  $Si-HfO<sub>2</sub>$  composite coatings is to inhibit the phase separation between  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$  while retaining the discrete distribution of the  $HfO<sub>2</sub>$  phase.

#### **5.2 Ion migration mechanism**

[Figure 1](#page-12-0)1 shows the TEM images of the Si30Hf composite after oxidation at 1370 ℃. The HfSiO<sub>4</sub> phase exhibited a continuous distribution inside the scale [\(Figs. 11](#page-12-0)(a) and 11(d)). By acting as an oxygen conduit, the continuous  $HfSiO<sub>4</sub>$  phase contributed to a greater oxidation rate than that of pure Si and Si20Hf [\(Fig. 6](#page-7-0) and [Table 1](#page-7-1)). Moreover, due to phase separation,  $HfSiO<sub>4</sub>$  phases were enriched at the surface [\(Figs. 11](#page-12-0)(a) and 11(d)). Phase separation results in the formation of a  $SiO<sub>2</sub>$ -rich zone underneath the  $HfSiO<sub>4</sub>$  layer [\(Fig. 11](#page-12-0)(a)). Due to the  $SiO<sub>2</sub>$ -rich zone, the oxidation rate is lower than that of Si-stabilizer duplex coatings [\[14](#page-13-12)]. In line with the XRD results [\(Fig. 3](#page-4-0)), tetragonal HfSiO<sub>4</sub> and  $\alpha$ -SiO<sub>2</sub> were detected [\(Figs. 1](#page-12-0)1(b) and 11(c)). Additionally, a large  $HfSiO<sub>4</sub>$ island is formed by the agglomeration of smaller particles [\(Fig](#page-12-0).  $11(a)$  $11(a)$ ). This suggests that the formation of HfSiO<sub>4</sub> occurs through the inward diffusion of  $SiO<sub>2</sub>$ . This is consistent with the smaller crystalline plane spacing of  $SiO<sub>2</sub>$  compared to that of HfSiO<sub>4</sub> and  $HfO<sub>2</sub>$  [\(Figs. 11](#page-12-0)(e) and 11(f)).

#### **5.3 Implications for more durable EBCs**

Compared to those of a pure Si coating, the Si-HfO<sub>2</sub> bond coating exhibits a significantly greater strength (~90 MPa) and creep rate  $(\sim 10^{-6} \text{ s}^{-1})$  at 1400 °C [[36](#page-13-34)]. However, reports indicate that the free Si within a 50  $\mu$ m thick Si-HfO<sub>2</sub> coating (25/75 mol% HfO<sub>2</sub>/Si) was completely oxidized within 10 h at 1371 ℃ [[17](#page-13-15)]. This rapid oxidation is attributed to the continuous distribution of the  $HfO<sub>2</sub>$ phase, which serves as an oxygen conduit. Conversely, the



<span id="page-11-0"></span>

**Fig. 10** Density functional study of the HfSiO<sub>4</sub>–SiO<sub>2</sub> and HfO<sub>2</sub>–SiO<sub>2</sub> interfaces: (a) HfSiO<sub>4</sub>–SiO<sub>2</sub> interface, (b) HfO<sub>2</sub>–SiO<sub>2</sub> interface, (c) vacancy at the HfSiO<sub>4</sub>–SiO<sub>2</sub> interface, and (d) total density of states.

composites with 10 and 20 mol%  $HfO<sub>2</sub>$  exhibit oxidation rates comparable to those of pure Si [\(Fig. 6](#page-7-0) and [Table 1](#page-7-1)). These findings emphasize the importance of maintaining a discrete distribution of the HfO<sub>2</sub> phase for enhanced oxidation resistance. Moreover, the coefficients of thermal expansion (CTEs) of the pure  $HfO<sub>2</sub>$  and Si–HfO<sub>2</sub> composites are  $5.8 \times 10^{-6}$  K<sup>-1</sup> and  $5 \times 10^{-6}$ –6 $\times 10^{-6}$  K<sup>-1</sup> [[15](#page-13-13)–17,[22](#page-13-20)], respectively, both of which are greater than those of SiC<sub>t</sub>/SiC CMCs [\[10](#page-13-8)]. This suggests potential tensile stresses in the composite during thermal cycling, leading to vertical cracking and interfacial delamination  $[18]$ . Therefore, controlling the HfO<sub>2</sub> content while maintaining a discrete distribution is crucial.

The suppression of the  $SiO<sub>2</sub>$  phase transition within the Si–HfO<sub>2</sub> composite relies on the reaction between  $SiO_2$  and HfO<sub>2</sub>. If the  $HfO<sub>2</sub>$  content falls below a critical level, phase-transitioninduced cracking is likely to occur, as evidenced by the mud cracking in the Si10Hf composite [\(Fig. 9](#page-10-0)(b)). Additionally, the

continuous distribution of  $HfO<sub>2</sub>$  in the Si30Hf composites results in an oxidation rate 1.8 times greater than that of pure Si at 1370 ℃ [\(Fig. 6](#page-7-0) and [Table](#page-7-1) 1). These results highlight that the composite with 20 mol% HfO<sub>2</sub> exhibits optimal resistance to cracking and oxidation. This insight is crucial for designing  $Si-HfO<sub>2</sub>$  powders and coatings to achieve extended service lifetimes at 1370 ℃.

The CTE of HfSiO<sub>4</sub> is approximately  $3.65 \times 10^{-6} - 4.55 \times 10^{-6}$  K<sup>-1</sup> [\[15](#page-13-13)[,16](#page-13-14)[,18](#page-13-16)[,37](#page-13-35)], which matches that of SiC and Si [\[10](#page-13-8)]. However, due to the significantly lower surface energy of  $HfSiO<sub>4</sub>$  [\(Fig. 10](#page-11-0)), phase separation occurred between  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$  during oxidation [\(Figs. 4](#page-5-0) and [8\)](#page-9-0). This phase separation is not conducive to inhibiting phase-transition-induced cracking and may lead to the formation of a fluorite-structured  $HfO<sub>2</sub>$  phase  $(F<sub>SS</sub>-HfO<sub>2</sub>)$  at the $HfO_2/Yb_2Si_2O_7$  interface [[22](#page-13-20)[,38](#page-13-36)]. The CTE of  $F_{SS}-HfO_2$  is much larger than that of the m-HfO<sub>2</sub> and SiC substrates, causing premature spallation of the EBCs. Thus, a promising avenue for



<span id="page-12-0"></span>

Fig. 11 TEM characterization results of Si–HfO<sub>2</sub> composite samples after isothermal oxidation at 1370 ℃: (a, d) cross-section and surface images, (b, c) selected-area diffraction (SAD) patterns of HfSiO<sub>4</sub> and α-SiO<sub>2</sub>, (e, f) HRTEM images at the HfO<sub>2</sub>/HfSiO<sub>4</sub> and HfSiO<sub>4</sub>/SiO<sub>2</sub> interfaces, and (g) HRTEM image of m-HfO<sub>2</sub>.

improving antioxidative  $Si-HfO<sub>2</sub>$  composite coatings involves inhibiting phase separation between  $HfSiO<sub>4</sub>$  and  $SiO<sub>2</sub>$  while retaining the discrete distribution of the  $HfO<sub>2</sub>$  phase.

# **6 Conclusions**

In this study,  $Si-HfO<sub>2</sub>$  dual-state duplex composite materials are proposed to enhance both the oxidation resistance and cracking resistance. The structural evolution, oxidation kinetics, and cracking behavior of the composite were characterized. The main conclusions are as follows:

1) The as-prepared composite has a structure comprising discrete HfO<sub>2</sub> "bricks" embedded in a continuous Si "mortar", while the oxidized state transforms into discrete  $HfSiO<sub>4</sub>$  "bricks" within continuous thin  $SiO<sub>2</sub>$  "mortars".

2) The continuous thin  $SiO<sub>2</sub>$  "mortars" effectively inhibit oxygen permeation, enabling the composite with 20 mol%  $HfO<sub>2</sub>$ to achieve an oxidation rate comparable to that of pure Si at 1300 and 1370 °C, despite the oxygen-conducting role of  $HfSiO<sub>4</sub>$ .

3) Discrete  $HfSiO<sub>4</sub>$  particles are beneficial for relieving phasetransition-induced stress and hindering crack propagation. Consequently, the lifetime of the composite with  $20 \text{ mol}$ % HfO<sub>2</sub> exceeds that of pure Si by more than 10 times at 1370 ℃.

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# **Declaration of competing interest**

The authors have no competing interests to declare that are relevant to the content of this article. The author Guanjun Yang is the Editorial Committee member of this journal.

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